

## 1. Description

BLP08N10G, the N-channel Enhanced Power MOSFETs, is obtained by advanced double trench technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. This is suitable device for Synchronous rectification and high speed switching applications.

### KEY CHARACTERISTICS

Parameter	Value	Unit
$V_{DSS}$	100	V
$I_D$	60	A
$R_{DS(on)}$ @10V.typ	7.5	$m\Omega$

### FEATURES

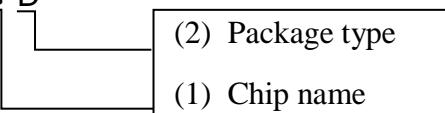
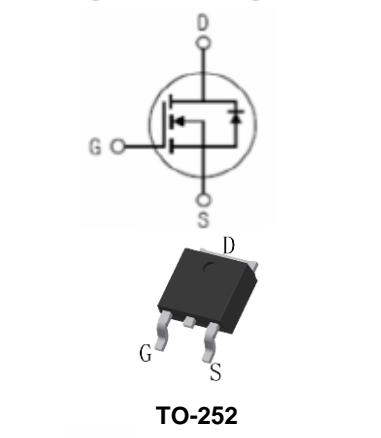
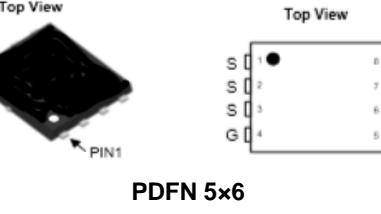
- Fast Switching
- Low On-Resistance
- Low Gate Charge
- Low Reverse transfer capacitances
- High avalanche ruggedness
- RoHS product

### APPLICATIONS

- Synchronous rectification
- High speed switching applications

## ORDERING INFORMATION

Ordering Codes	Package	Product Code	Packing
BLP08N10G-D	TO-252	P08N10G	Reel
BLP08N10G-Q	PDFN5X6	P08N10G	Reel

<u>BLP08N10G-D</u>  (1) BLP08N10G 8mΩ/100V (2) D: TO-252 Q: PDFN5X6	  
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## 2. ABSOLUTE RATINGS

at  $T_C=25^\circ\text{C}$ , unless otherwise specified

Symbol	Parameter	Rating	Units
$V_{DSS}$	Drain-Source Voltage	100	V
$I_D$	Continuous Drain Current, Silicon Limited	66	A
	Continuous Drain Current, Package Limited	60	A
	Continuous Drain Current @ $T_C=100^\circ\text{C}$ , Silicon Limited	42.3	A
$I_{DM}$ Note1	Pulsed Drain Current	240	A
$V_{GS}$	Gate-Source Voltage	$\pm 20$	V
$E_{AS}$ Note2	Avalanche Energy	156	mJ
$P_D$	Power Dissipation	73.5	W
	Derating Factor above $25^\circ\text{C}$	0.59	W/ $^\circ\text{C}$
$T_J, T_{stg}$	Operating Junction and Storage Temperature Range	150, -55 to 150	$^\circ\text{C}$
$T_L$	Maximum Temperature for Soldering	260	$^\circ\text{C}$

Note1: Repetitive Rating: Pulse width limited by maximum junction temperature

Note2: L=0.5mH, Ias=25A, Start  $T_J=25^\circ\text{C}$

## 3. Thermal characteristics

Symbol	Parameter	Max	Units
$R_{\theta JC}$	thermal resistance, Junction-Case	1.7	$^\circ\text{C/W}$
$R_{\theta JA}$	thermal resistance, Junction-Ambient	62.5	$^\circ\text{C/W}$

## 4. Electrical Characteristics

at  $T_C=25^\circ\text{C}$ , unless otherwise specified

OFF Characteristics						
Symbol	Parameter	Test Conditions	Values			Units
			Min	Typ	Max	
$V_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}, I_D=250\mu\text{A}$	100	110	--	V
$I_{DSS}$	Drain-Source Leakage Current	$V_{DS}=100\text{V}, V_{GS}=0\text{V}$	--	--	1	$\mu\text{A}$
		$V_{DS}=80\text{V}, V_{GS}=0\text{V}$ $@ T_C=125^\circ\text{C}$	--	--	100	$\mu\text{A}$
$I_{GSS(F)}$	Gate-Source Forward Leakage	$V_{GS}=+20\text{V}$	--	--	100	nA
$I_{GSS(R)}$	Gate-Source Reverse Leakage	$V_{GS}=-20\text{V}$	--	--	-100	nA

**ON Characteristics**

Symbol	Parameter	Test Conditions	Values			Unit
			Min	Typ	Max	
$R_{DS(on)}$	Drain-Source On-Resistance	$V_{GS}=10V, I_D=30A$	--	7.5	8	$m\Omega$
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	2	3	4	V
Pulse width $t_p \leq 300\mu s, \delta \leq 2\%$						

**Dynamic Characteristics**

Symbol	Parameter	Test Conditions	Values			Units
			Min	Typ	Max	
$C_{iss}$	Input Capacitance	$V_{DS}=50V, V_{GS}=0, f=1MHz$	--	2350	--	pF
$C_{oss}$	Output Capacitance		--	670	--	
$C_{rss}$	Reverse Transfer Capacitance		--	10	--	
$Q_g$	Total Gate Charge	$V_{DD}=50V, I_D=30A, V_{GS}=10V$	--	44.5	--	nC
$Q_{gs}$	Gate-Source charge		--	12.9	--	
$Q_{gd}$	Gate-Drain charge		--	10.8	--	
$R_G$	Gate resistance	$V_{GS}=0, V_{DS}=0$		1.1		$\Omega$

**Switching Characteristics**

Symbol	Parameter	Test Conditions	Values			Units
			Min	Typ	Max	
$t_{d(on)}$	Turn-On Delay Time	$V_{DD}=50V, I_D=30A, V_{GS}=10V, R_G=5\Omega, \text{ Resistive Load}$	--	15	--	ns
$t_r$	Rise Time		--	10	--	
$t_{d(off)}$	Turn-Off Delay Time		--	33	--	
$t_f$	Fall Time		--	13	--	

**Source-Drain Diode Characteristics**

Symbol	Parameter	Test Conditions	Values			Units
			Min	Typ	Max	
$I_s$	Continuous Source Current	$V_{GS}=0V, I_s=30A$	--	--	60	A
$I_{SM}$	Maximum Pulsed Current		--	--	240	A
$V_{SD}$	Diode Forward Voltage	$V_{GS}=0V, I_s=30A$	--	--	1.2	V
$T_{rr}$	Reverse Recovery Time	$I_s=30A, V_{GS}=0, di/dt=100A/us$	--	43	--	ns
$Q_{rr}$	Reverse Recovery Charge		--	114	--	nC

## 5. Characteristics Curves

Figure 1. Safe Operating Area

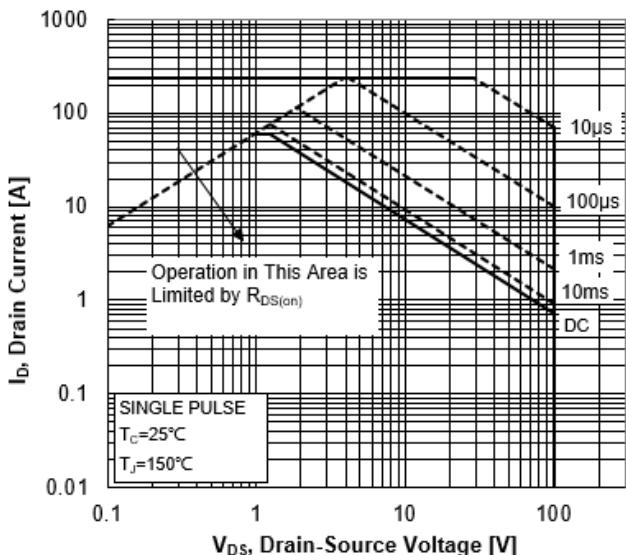


Figure 2. Maximum Power Dissipation vs Case Temperature

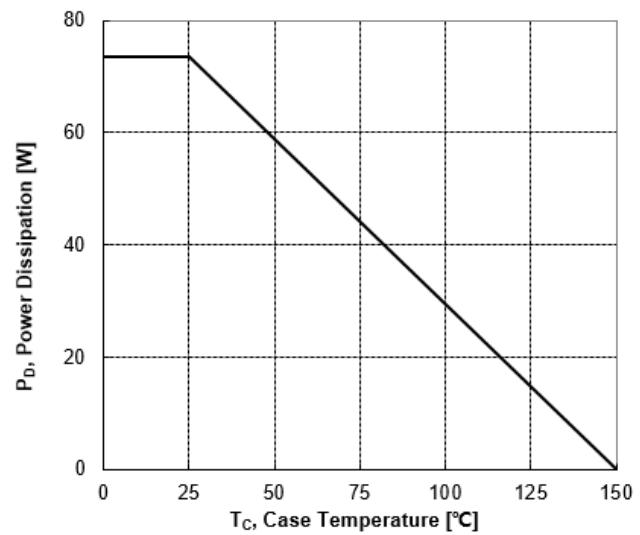


Figure 3. Maximum Continuous Drain Current vs Case Temperature

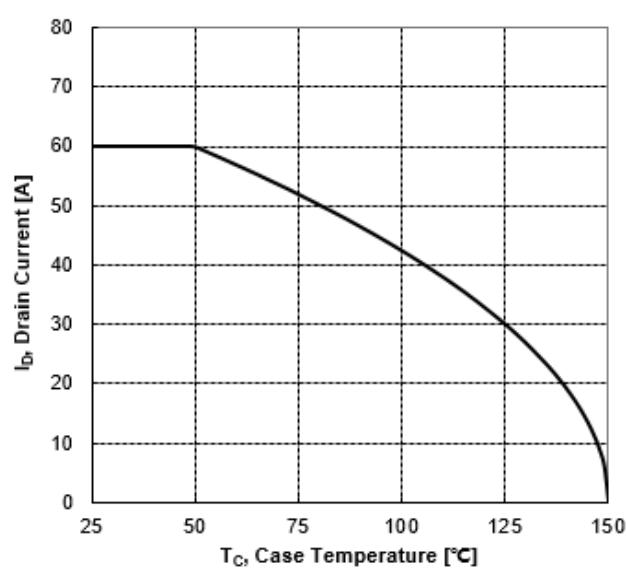
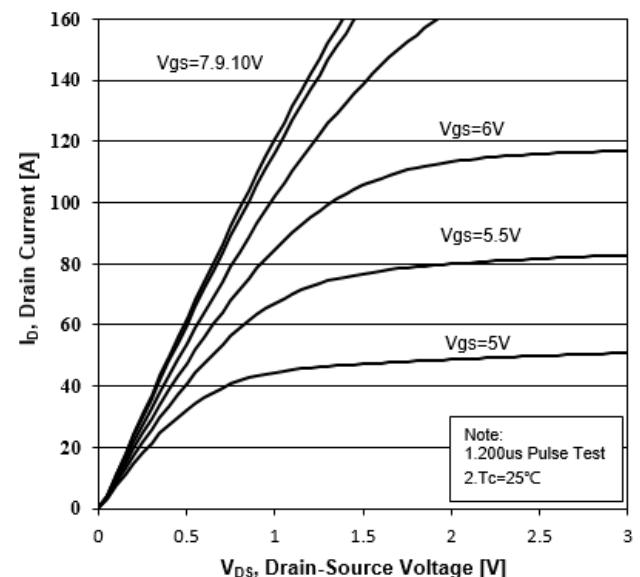
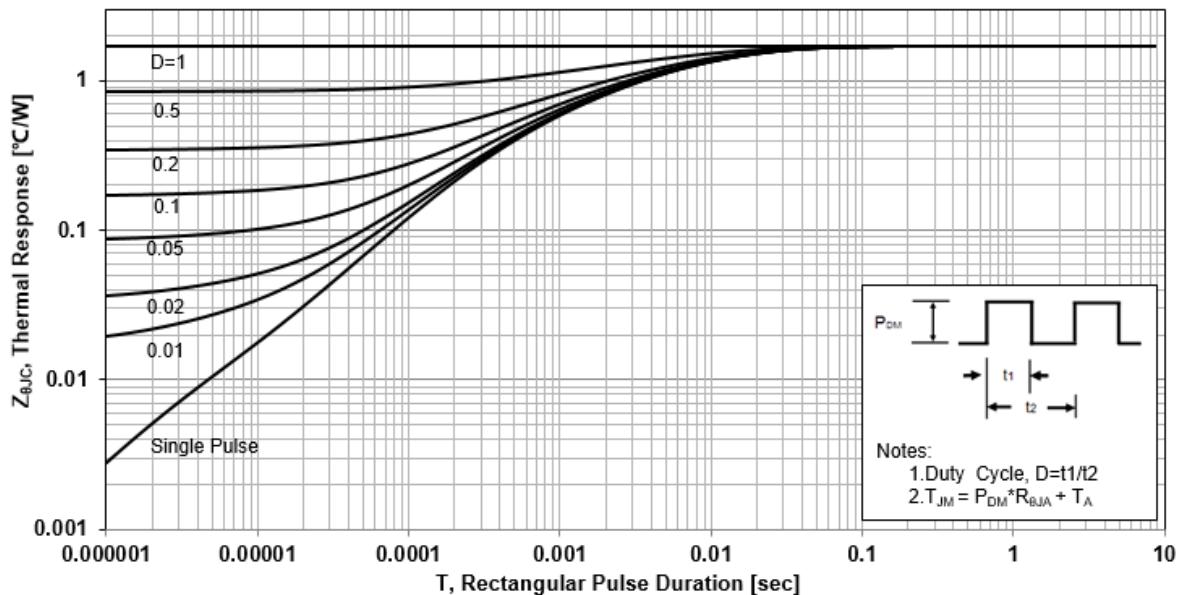


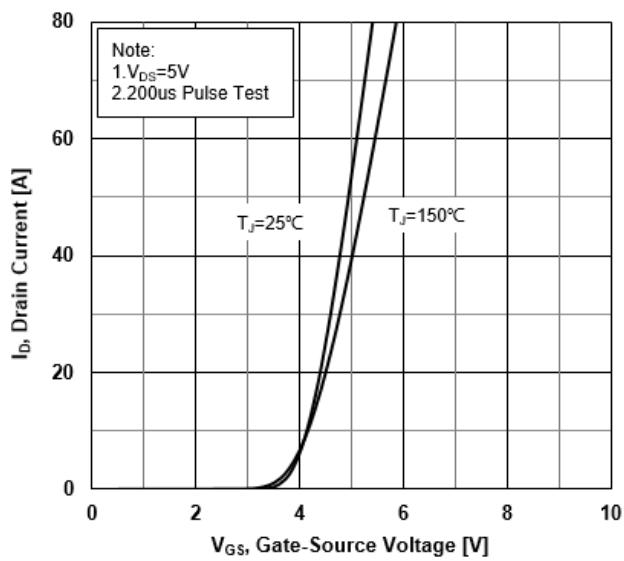
Figure 4. Typical Output Characteristics



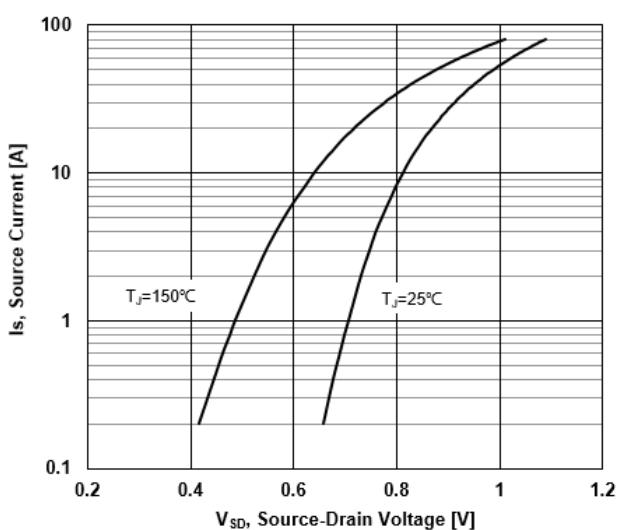
**Figure 5. Transient Thermal Impedance**

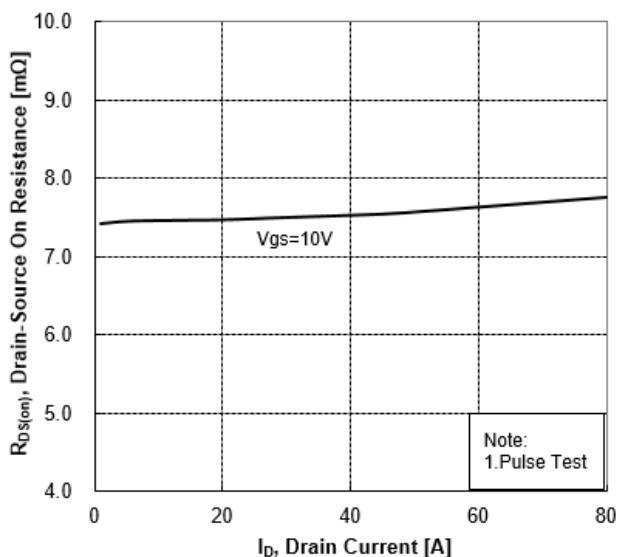
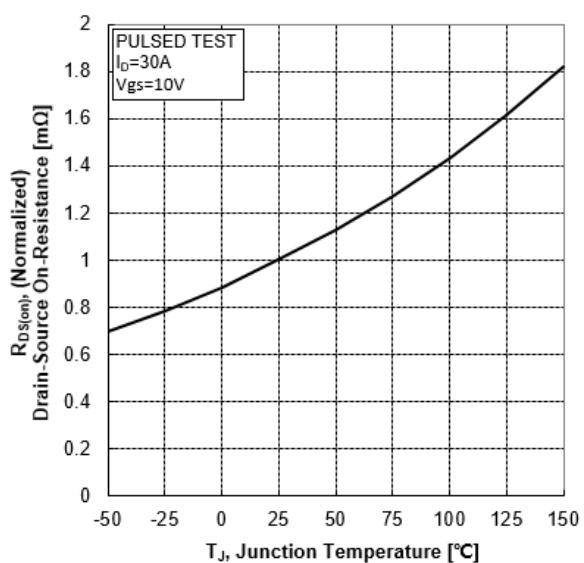
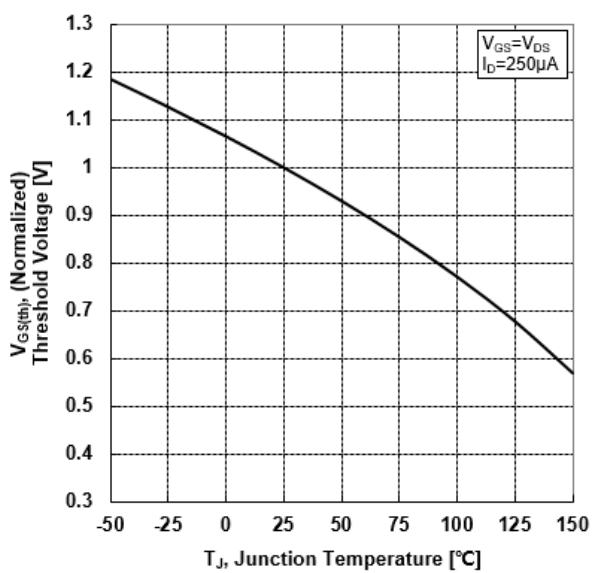
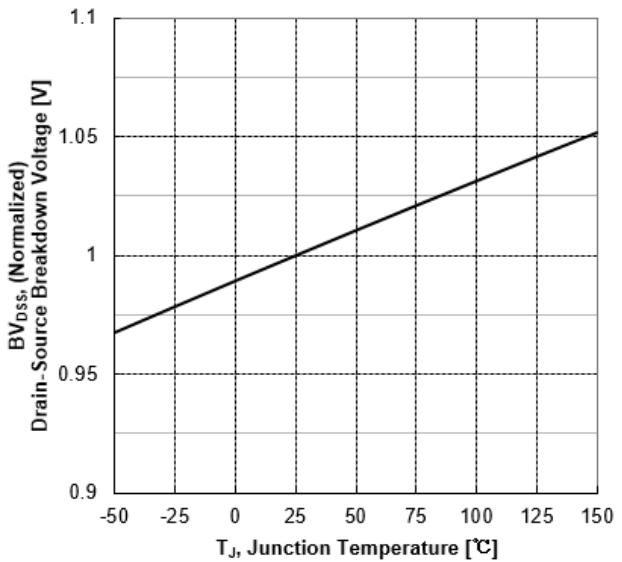


**Figure 6. Typical Transfer Characteristics**

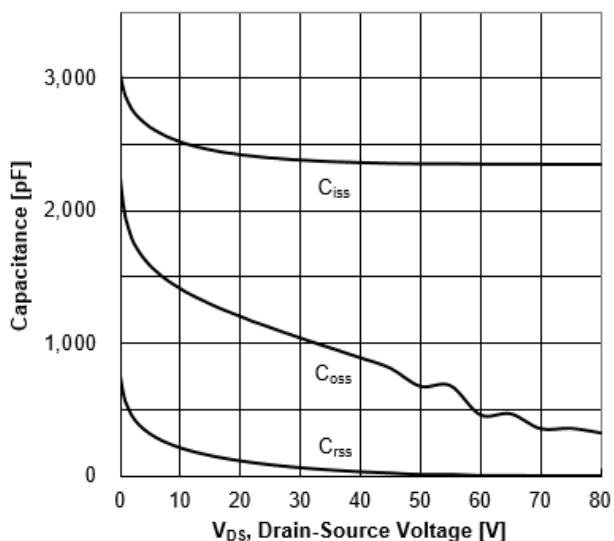


**Figure 7. Source-Drain Diode Forward Characteristics**

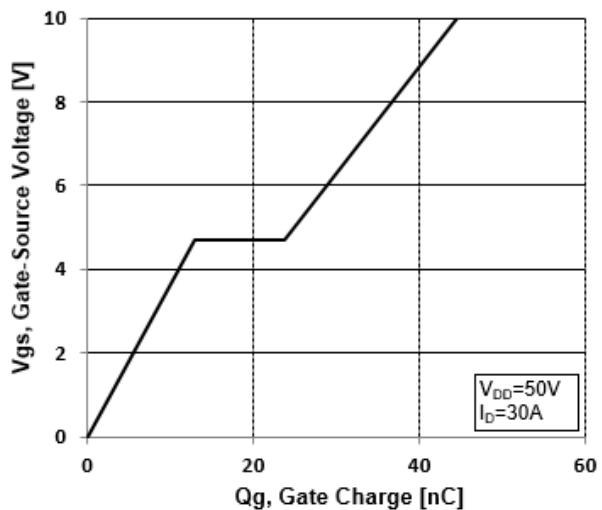


**Figure 8. Drain-Source On-Resistance vs Drain Current**

**Figure 9. Normalized On-Resistance vs Junction Temperature**

**Figure 10. Normalized Threshold Voltage vs Junction Temperature**

**Figure 11. Normalized Breakdown Voltage vs Junction Temperature**


**Figure 12. Capacitance Characteristics**



**Figure 13. Typical Gate Charge vs Gate-Source Voltage**



## 6. Test Circuit and Waveform

Figure 14. Resistive Switching Test Circuit

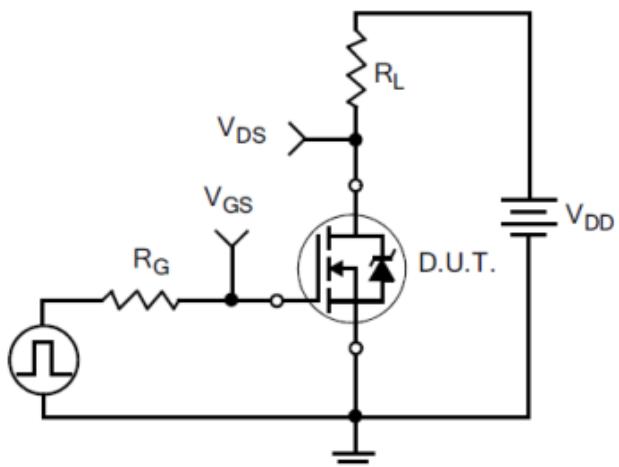


Figure 15. Resistive Switching Waveforms

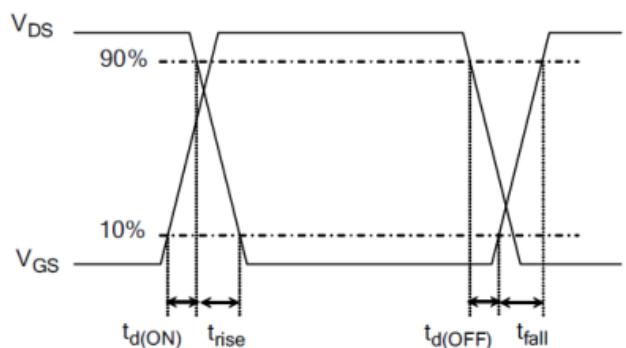


Figure 16. Gate Charge Test Circuit

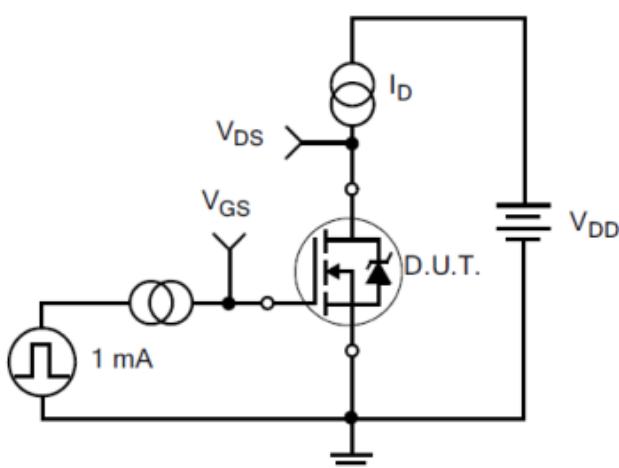
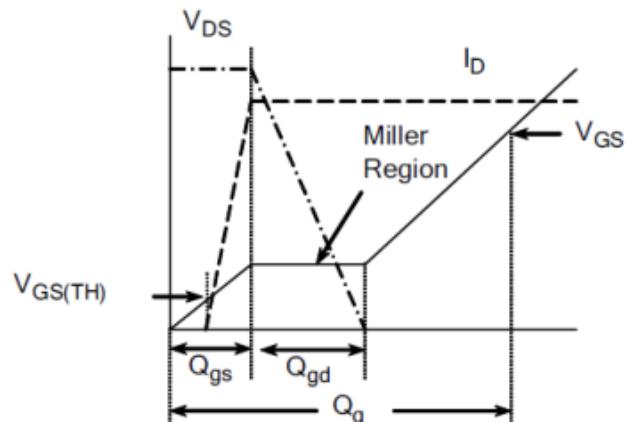
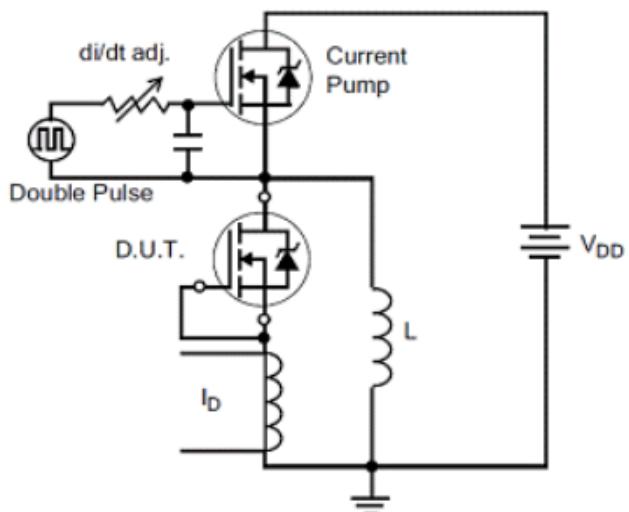
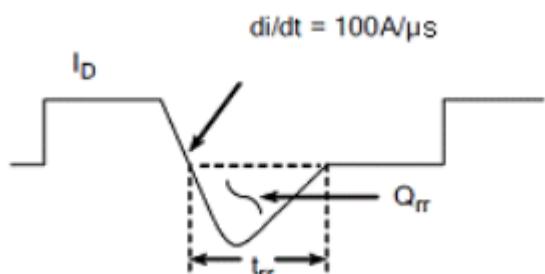
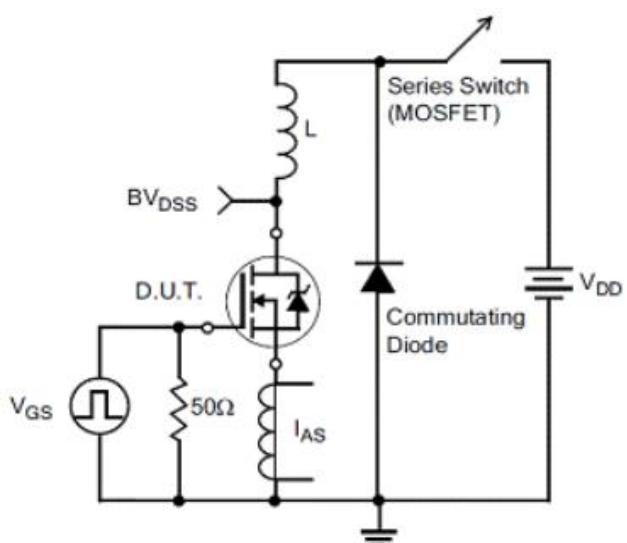
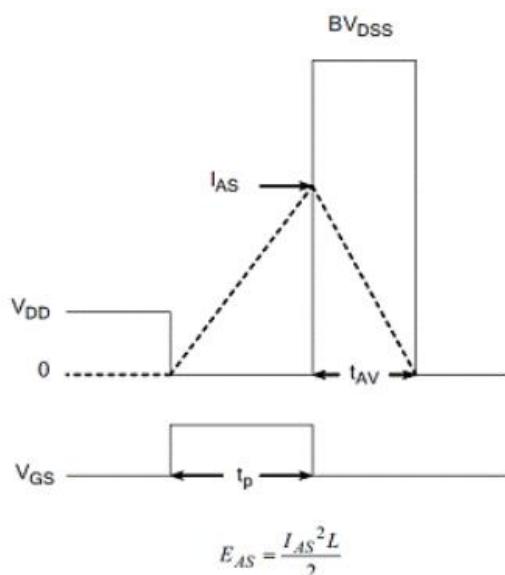


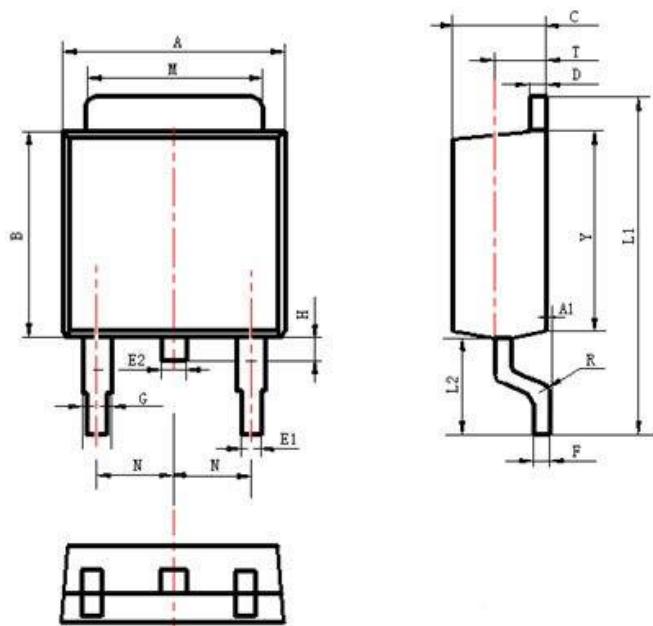
Figure 17. Gate Charge Waveforms



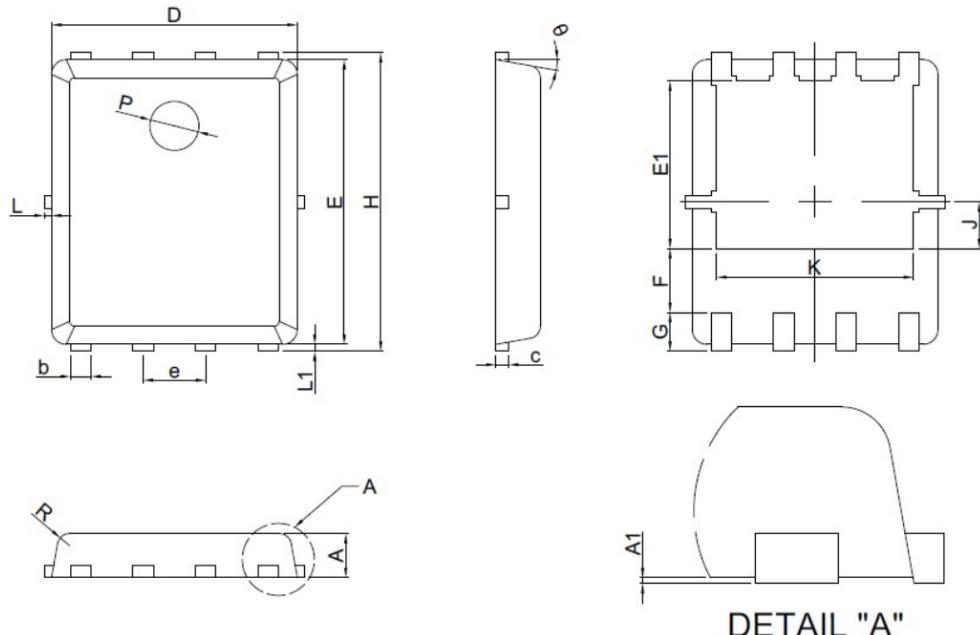
**Figure 18. Diode Reverse Recovery Test Circuit**

**Figure 19. Diode Reverse Recovery Waveform**

**Figure 20. Unclamped Inductive Switching Test Circuit**

**Figure 21. Unclamped Inductive Switching Waveform**


## 7. Package Description

TO-252



Items	Values(mm)	
	MIN	MAX
A	6.30	6.90
A1	0	0.13
B	5.70	6.30
C	2.10	2.50
D	0.30	0.60
E1	0.60	0.90
E2	0.70	1.00
F	0.30	0.60
G	0.70	1.20
L1	9.60	10.50
L2	2.70	3.10
H	0.60	1.00
M	5.10	5.50
N	2.09	2.49
R	0.3	0.3
T	1.40	1.60
Y	5.10	6.30

**PDFN5\*6**


SYMBOL	MIN	NORMAL	MAX
A	0.8	0.9	1.0
A1	0.00	0.03	0.05
b	0.35	0.42	0.49
c	0.254REF		
D	4.9	5.0	5.1
F	1.40REF		
E	5.7	5.8	5.9
e	1.27BSC		
H	5.95	6.08	6.20
L1	0.10	0.14	0.18
G	0.60REF		
K	4.00REF		
L	-----	-----	0.15
J	0.95BSC		
P	1.00REF		
E1	3.35	3.40	3.65
θ	6°	10°	14°
R	0.25REF		

## 联系我们

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主营产品线有 LDO、DC/DC、AC-DC、电压检测器、充电 IC、负载开关 IC、保险丝、多功能集成保护 IC、功率 TVS 管、二三级管、PMU、马达驱动、LED 驱动、功率器件、数字电源、Hall IC、磁组、传感器 IC、汽容胶传感器、压力传感器、位移传感器、惯导模块、锂电保护芯片、微动开关、IGBT、PTC、ESD、EEPROM, 8bit/32bit MCU, PMIC、中低压 MOS 管、高压 COOL MOS、高压平面 MOSFET 等。

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